DesignCon 2013 IBIS Summit Santa Clara, CA January 31, 2013

AMI Model-to-Hardware Correlation

Greg Edlund IBM gedlund@us.ibm.com

TX Eye Measurement



RX Eye Measurement



TX Model Parameters

Function	Analog Buffer Model (.ibs)	Algorithmic Model (.ami)
Output stage supply voltage	[Voltage Range]	
Output stage impedance	[Pulldown], [Pullup]	
Rise time	[Ramp], [Rising Waveform]	
Fall Time	[Ramp], [Falling Waveform]	
Capacitance	C_comp	
Jitter		Tx_Jitter <mark>(</mark> DjRj)
De-emphasis		txtaps (0, 1)

TX Block Diagram



GND

D10.2 Pattern 0.6 m Cable

Parameter	Symbol	Sim	Meas	Std Dev	SAS-2	Units
Height, p-p differential	Н	657	748	3	n/a	mV
Width	W	162	155	1	n/a	ps
Rise Time, 20-80%	TR	47	59.7	1.0	42	ps
Fall Time, 20-80%	TF	47	59.1	1.1	42	ps
Total Jitter	ТJ	12.50	12.10	0.84	42	ps
Random Jitter, rms	RJ	0.88	0.53	0.02	25	ps
Deterministic Jitter	DJ	0.00	5.31	0.90	n/a	ps
Data Dependent Jitter	DDJ	0.04	0.00	0.00	n/a	ps
Periodic Jitter	PJ	0.02	5.31	0.90	n/a	ps

D10.2 Pattern 0.6 m Cable

Simulation

Measurement



PRBS-7 Pattern 0.6 m Cable

Parameter	Symbol	Sim	Meas	Std Dev	SAS-2	Units
Height, p-p differential	н	582	673	3	n/a	mV
Width	W	150	137	0.99	n/a	ps
Total Jitter	TJ	21.92	30.00	0.99	42	ps
Random Jitter, rms	RJ	0.87	0.57	0.03	25	ps
Deterministic Jitter	DJ	9.50	23.54	0.93	n/a	ps
Data Dependent Jitter	DDJ	12.05	15.98	0.01	n/a	ps
Periodic Jitter	PJ	0.08	5.30	0.93	n/a	ps

PRBS-7 Pattern 0.6 m Cable

600 400 200 673 mV x 137 ps 582 mV x 150 ps 0 -200 -400 Eye: All Bits Offset: -0.0085543 -600 00:59994, Total:247996 :2039888 50 100 150 200 250 300 -150 -100 -50 50 100 150 0 O mV ps ps

Simulation

Measurement



Parameter	Old	New	Units
[Ramp]	14	8	V/ns
Tap 0	1.00	1.05	
Eye height measurement point	40-60	49-51	%
Maximum impulse response frequency	n/a	50	GHz
Number of points per UI	32	128	
[Voltage Range]	1.000	1.007	V

D10.2 Pattern 0.6 m Cable

Parameter	Symbol	Sim	Meas	Std Dev	SAS-2	Units
Height, p-p differential	н	731	748	3	n/a	mV
Width	W	162	155	1	n/a	ps
Rise Time, 20-80%	TR	55	59.7	1.0	42	ps
Fall Time, 20-80%	TF	55	59.1	1.1	42	ps
Total Jitter	ТJ	12.70	12.10	0.84	42	ps
Random Jitter, rms	RJ	0.89	0.53	0.02	25	ps
Deterministic Jitter	DJ	0.00	5.31	0.90	n/a	ps
Data Dependent Jitter	DDJ	0.02	0.00	0.00	n/a	ps
Periodic Jitter	PJ	0.03	5.31	0.90	n/a	ps

PRBS-7 Pattern 0.6 m Cable

Parameter	Symbol	Sim	Meas	Std Dev	SAS-2	Units
Height, p-p differential	Н	642	673	3	n/a	mV
Width	W	148	137	0.99	n/a	ps
Total Jitter	TJ	23.77	30.00	0.99	42	ps
Random Jitter, rms	RJ	0.88	0.57	0.03	25	ps
Deterministic Jitter	DJ	11.25	23.54	0.93	n/a	ps
Data Dependent Jitter	DDJ	13.91	15.98	0.01	n/a	ps
Periodic Jitter	PJ	0.00	5.30	0.93	n/a	ps

PRBS-7 Pattern 0.6 m Cable

Simulation

Measurement



Interconnect Models



Cable Assy. S-Parameters



0.6 m Cable Step Response



PRBS-7 Pattern 3.25 m Cable

Cable	Parameter	Symbol	Sim	Meas	Units
1.2 m	Height, p-p differential	н	575	582	mV
	Width	W	145	130	ps
2.5 m	Height, p-p differential	н	344	344	mV
	Width	W	121	113	ps
3.25 m	Height, p-p differential	н	262	252	mV
	Width	W	102	90	ps

PRBS-7 Pattern 3.25 m Cable



RX Block Diagram



GND

RX Eye w/ & w/o AGC

PRBS-7 Pattern 3.25 m Cable



RX Eye at Latch

PRBS-7 Pattern

Cable	Parameter	Symbol	Sim	Meas	Units
0.6 m	Height, p-p differential	н	382	237	mV
1.2 m			346	248	mV
2.5 m			274	240	mV
3.25 m			246	230	mV
10.0 m			114	208	mV
15.0 m			n/a	115	mV
0.6 m	Width	W	134	153	ps
1.2 m			145	147	ps
2.5 m			124	151	ps
3.25 m			139	151	ps
10.0 m			135	119	ps
15.0 m			n/a	58	ps

AMI Acceptance Criteria

ACCURACY

- Features that affect S11 not included in algorithmic model
- No double counting of package, e.g. s-parameters and .ibs file
- No double counting of C_Comp, e.g. s-parameters and .ibs file
- S-parameters for test channel distributed with model
- Expected jitter and eye dimensions for test channel
- PHY supports on-chip oscilloscope GUI running on PC
- PHY outputs D10.2 & PRBS-7 patterns with oscilloscope connected
- Demo board to include 2.92 mm connection to TX, max 2 in. wire

AMI Acceptance Criteria

ACCURACY

- Lab report to include:
 - a. TX jitter decomposition measurements
 - b. RX stressed eye testing
 - c. Model-to-hardware correlation
 - d. Proof of industry standard compliance

COMPLETENESS

DOCUMENTATION

FUNCTIONALITY

Conclusions

- IBIS-AMI model development requires IO circuit engineering and programming skills.
- IBIS-AMI model development is a LOT of work!
 - Supplier could spend 2 4 person months.
 - Customer could spend 1 2 person months.
- Estimate work load and capital equipment.
- Clarify expectations before buying.